

EAST Search History

10/520,729

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|---------|---|---|------------------|---------|------------------|
| L1 | 4336734 | semiconductor or integrated adj circuit\$1 or ic\$1 or die\$1 or dice\$1 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/02/02 07:46 |
| L2 | 968486 | 1 and light | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/02/02 07:46 |
| L3 | 20146 | 2 and focus\$4 near beam | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/02/02 07:47 |
| L4 | 12213 | 3 and scan\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/02/02 07:47 |
| L5 | 25 | 4 and high\$1contrast near imag\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/02/02 07:55 |
| L6 | 9644 | 4 and imag\$4 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/02/02 07:56 |
| L7 | 161 | 6 and (obic or optical near beam near induc\$4 near current\$1) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/02/02 07:57 |